

Notice of References Cited	Application/Control No. 10/577,786		Applicant(s)/Patent Under Reexamination BACHMANN ET AL.	
	Examiner Ryan D. Coyer		Art Unit 2191	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,311,265	10-2001	Beckerle et al.	712/203
*	B	US-6,330,008	12-2001	Razdow et al.	715/772
*	C	US-7,200,448	04-2007	Cachat et al.	700/18
*	D	US-7,343,585	03-2008	Lau et al.	717/108
*	E	US-7,174,536	02-2007	Kothari et al.	717/109
*	F	US-7,143,087	11-2006	Fairweather, John	707/770
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	National Instruments, Inc., "LabView User Manual", April, 2003, Part Number 32099E-01.			
	V	The Mathworks, Inc., "Simulink Model-Based and System-Based Design", September 2003, ver. 5.1.			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.